Power MOSFET

-20 V, -5.3 A, P-Channel ChipFET™

Features

- Low R_{DS(on)}
- Higher Efficiency Extending Battery Life
- Logic Level Gate Drive
- Miniature ChipFET Surface Mount Package
- Pb–Free Package is Available

Applications

• Power Management in Portable and Battery–Powered Products; i.e., Cellular and Cordless Telephones and PCMCIA Cards

			•	
Rating	Symbol	5 sec	Steady State	Unit
Drain-Source Voltage	V _{DS}	-2	20	V
Gate-Source Voltage	V _{GS}	±	12	V
Continuous Drain Current $(T_J = 150^{\circ}C)$ (Note 1) $T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	Ι _D	-5.3 -3.8	-3.9 -2.8	A
Pulsed Drain Current	I _{DM}	±	20	А
Continuous Source Current (Note 1)	I _S	-5.3	-3.9	A
Maximum Power Dissipation (Note 1) $T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	P _D	2.5 1.3	1.3 0.7	W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	–55 to	o +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.27 in sq [1 oz] including traces).



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
–20 V	46 mΩ @ –4.5 V	–5.3 A



P-Channel MOSFET



ORDERING INFORMATION

Device	Package	Shipping [†]
NTHS5441T1	ChipFET	3000/Tape & Reel
NTHS5441T1G	ChipFET (Pb–Free)	3000/Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL CHARACTERISTICS

Characteristic	Symbol	Тур	Max	Unit
Maximum Junction–to–Ambient (Note 2) t ≤ 5 sec Steady State	$R_{ heta JA}$	40 80	50 95	°C/W
Maximum Junction-to-Foot (Drain) Steady State	R_{\thetaJF}	15	20	°C/W

ELECTRICAL CHARACTERISTICS (T_J = $25^{\circ}C$ unless otherwise noted)

Characteristic Symbol Test Conditi		Test Condition	Min	Тур	Max	Unit	
Static							

Static						
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-0.6		-1.2	V
Gate-Body Leakage	I _{GSS}	V_{DS} = 0 V, V_{GS} = ±12 V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -16 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			-1.0	μΑ
		$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 85^{\circ}\text{C}$			-5.0	
On-State Drain Current (Note 3)	I _{D(on)}	V_{DS} \leq –5.0 V, V_{GS} = –4.5 V	-20			А
Drain-Source On-State Resistance (Note 3)	r _{DS(on)}	V_{GS} = -3.6 V, I _D = -3.7 A V_{GS} = -4.5 V, I _D = -3.9 A		0.050 0.046	0.06 -	Ω
		$V_{GS} = -2.5 \text{ V}, \text{ I}_{D} = -3.1 \text{ A}$		0.070	0.083	
Forward Transconductance (Note 3)	9 _{fs}	V _{DS} = -10 V, I _D = -3.9 A		12		mhos
Diode Forward Voltage (Note 3)	V _{SD}	$I_{S} = -2.1 \text{ A}, V_{GS} = 0 \text{ V}$		-0.8	-1.2	V

Dynamic (Note 4)

Total Gate Charge	Q _G		9.7	22	nC
Gate-Source Charge	Q _{GS}	$V_{DS} = -10 \text{ V}, \text{ V}_{GS} = -4.5 \text{ V},$ $I_{D} = -3.9 \text{ A}$	1.2		
Gate-Drain Charge	Q _{GD}		3.6		
Input Capacitance	C _{iss}		710		pF
Output Capacitance	C _{oss}	$V_{DS} = -5.0 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, f = 1.0 \text{ MHz}$	400		
Reverse Transfer Capacitance	C _{rss}		140		
Turn–On Delay Time	t _{d(on)}		14	30	ns
Rise Time	t _r	$V_{\text{DD}} = -10 \text{ V}, \text{ R}_{\text{L}} = 10 \Omega$ $I_{\text{D}} \simeq -1.0 \text{ A}, \text{ V}_{\text{GEN}} = -4.5 \text{ V},$	22	55	
Turn–Off Delay Time	t _{d(off)}	$R_{\rm G} = 6 \Omega$	42	100	
Fall Time	t _f		35	70	1
Source-Drain Reverse Recovery Time	t _{rr}	I _F = -1.1 A, di/dt = 100 A/μs	30	60	

Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.27 in sq [1 oz] including traces).
Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Guaranteed by design, not subject to production testing.

TYPICAL ELECTRICAL CHARACTERISTICS



Temperature



TYPICAL ELECTRICAL CHARACTERISTICS



Figure 8. Normalized Thermal Transient Impedance, Junction-to-Ambient



PACKAGE DIMENSIONS

ChipFET[™] CASE 1206A-03 ISSUE G





- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETER. 3. MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE. 4. LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM. 5. DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS. 6. NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
- SURFACE.

	MILLIMETERS				INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	1.00	1.05	1.10	0.039	0.041	0.043	
b	0.25	0.30	0.35	0.010	0.012	0.014	
С	0.10	0.15	0.20	0.004	0.006	0.008	
D	2.95	3.05	3.10	0.116	0.120	0.122	
E	1.55	1.65	1.70	0.061	0.065	0.067	
е		0.65 BSC			0.025 BSC)	
e1		0.55 BSC			0.022 BSC		
L	0.28	0.35	0.42	0.011	0.014	0.017	
HE	1.80	1.90	2.00	0.071	0.075	0.079	
θ		5° NOM			5° NOM		

SOLDERING FOOTPRINT*



Basic

Styles 1 and 4

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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